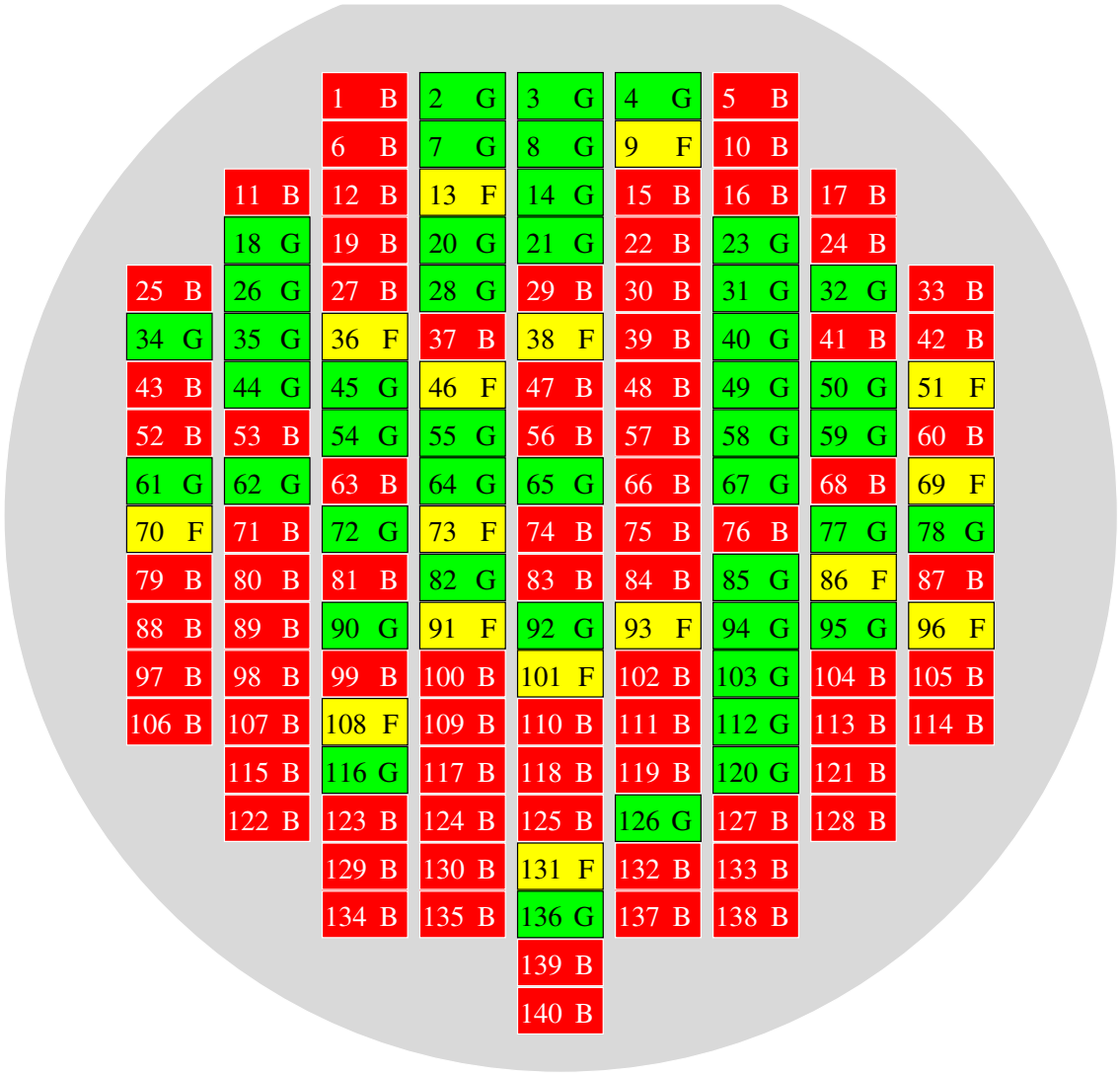
Die quality map for wafer 156 s/n: Y21316-08-16

Date: 06/16/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged